

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Applicants: Yasumaro KOMIYA, et al.
Serial No.: not yet assigned
Filed: April 29, 2005
For: DEFECT ANALYSIS APPARATUS, SYSTEM AND METHOD
FOR SEMICONDUCTOR INTEGRATED CIRCUIT
Group: not yet assigned

PRELIMINARY AMENDMENT

Commissioner for Patents
P.O. Box 1450
Alexandria, VA 22313-1450

April 29, 2005

Sir:

Prior to examination, please amend the above-identified application as follows.

Amendments to the Claims

Remarks are included following the amendments.